

Search Notes**Application/Control No.**

10/692,269

Examiner

HABTE MERED

Applicant(s)/Patent under Reexamination

LIAO ET AL.

Art Unit

2474

SEARCHED

Class	Subclass	Date	Examiner
370	230	11/6/2009	HM
370	230.1	11/6/2009	HM
370	231	11/6/2009	HM
370	232	11/6/2009	HM
370	233	11/6/2009	HM
370	234	11/6/2009	HM
370	449	11/6/2009	HM
709	225-229	11/6/2009	HM
455	450	11/6/2009	HM
455	452.1	11/6/2009	HM
455	452.2	11/6/2009	HM
455	453	11/6/2009	HM

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched East DB:USPAT, USPG-Pub, EPO and JPO	11/6/2009	HM
Searched IEEE	5/14/2009	HM
Searched Palm Inventor's DB	5/14/2009	HM
Consulted with SPE (A. Moe) on rejection strategy and allowable subject matter	5/12/2009	HM